

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10639925	PREIKSZAS ET AL.
Examiner	Art Unit	
TOAN M LE	2863	

SEARCHED

Class	Subclass	Date	Examiner
702	107, 85	2/11/08	TL
250	396R, 201.3, 311	2/11/08	TL
359	383, 17	2/11/08	TL
382	255	2/11/08	TL

SEARCH NOTES

Search Notes	Date	Examiner
702/107, 85; 250/396R, 201.3, 311; 359/383, 17; 382/255 (Electron Microscope Tune Index Interpolation)	2/11/08	TL
Electron Microscope Tune Index Interpolate	2/11/08	TL
East- See Search History Printout	2/13/08	TL
IEEE Xplore, ScienceDirect, Web Search	2/13/08	TL

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner